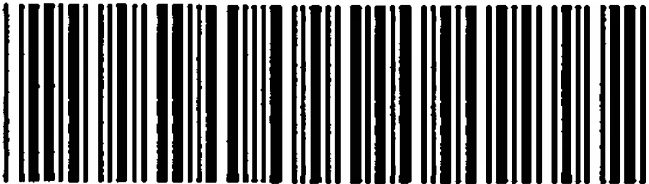


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/624,298	ZHANG ET AL.	
	Examiner	Art Unit	
	TUYEN T. NGUYEN	2832	

SEARCHED			
Class	Subclass	Date	Examiner
336	65, 83, 200, 206-208, 232	5/28/2005	TTN
257	531	5/28/2005	TTN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR